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Applied Scanning Probe Methods XI

Scanning Probe
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Preface for Applied Scanning Probe Methods Vol. XI–XIII

The extremely positive response by the advanced community to the Springer series on Applied Scanning Probe Methods I–X as well as intense engagement of the researchers working in the field of applied scanning probe techniques have led to three more volumes of this series. Following the previous concept, the chapters were focused on development of novel scanning probe microscopy techniques in Vol. XI, characterization, i.e. the application of scanning probes on various surfaces in Vol. XII, and the application of SPM probe to biomimetics and industrial applications in Vol. XIII. The three volumes will complement the previous volumes I–X, and this demonstrates the rapid development of the field since Vol. I was published in 2004. The purpose of the series is to provide scientific background to newcomers in the field as well as provide the expert in the field sound information about recent development on a worldwide basis.

Vol. XI contains contributions about recent developments in scanning probe microscopy techniques. The topics contain new concepts of high frequency dynamic SPM technique, the use of force microscope cantilever systems as sensors, ultrasonic force microscopy, nanomechanical and nanoindentation methods as well as dissipation effects in dynamic AFM, and mechanisms of atomic friction.

Vol. XII contains contributions of SPM applications on a variety of systems including biological systems for the measurement of receptor–ligand interaction, the imaging of chemical groups on living cells, and the imaging of chemical groups on live cells. These biological applications are complemented by nearfield optical microscopy in life science and adhesional friction measurements of polymers at the nanoscale using AFM. The probing of mechanical properties by indentation using AFM, as well as investigating the mechanical properties of nanocontacts, the measurement of viscous damping in confined liquids, and microtension tests using *in situ* AFM represent important contributions to the probing of mechanical properties of surfaces and materials. The atomic scale STM can be applied on heterogeneous semiconductor surfaces.

Vol. XIII, dealing with biomimetics and industrial applications, deals with a variety of unconventional applications such as the investigations of the epicuticular grease in potato beetle wings, mechanical properties of mollusc shells, electro-oxidative lithography for bottom-up nanofabrication, and the characterization of mechanical properties of biotool materials. The application of nanomechanics as tools for the investigation of blood clotting disease, the study of piezo-electric polymers, quantitative surface characterization, nanotribological characterization of

carbonaceous materials, and aging studies of lithium ion batteries are also presented in this volume.

We gratefully acknowledge the support of all authors representing leading scientists in academia and industry for the highly valuable contribution to Vols. XI–XIII. We also cordially thank the series editor Marion Hertel and her staff members Beate Siek and Joern Mohr from Springer for their continued support and the organizational work allowing us to get the contributions published in due time.

We sincerely hope that readers find these volumes to be scientifically stimulating and rewarding.

August 2008

Bharat Bhushan
Harald Fuchs

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